

Silicon Nanoelectronics Workshop 2023 (SNW 2023)

June 11th-12th, 2023

Rihga Royal Hotel Kyoto, Kyoto, Japan

Sunday, June 11th, 2023

8:45 Opening remarks

Katsuhiro Tomioka, *Hokkaido Univ.*

Session 1: Plenary

Session Chair: Katsuhiro Tomioka, *Hokkaido Univ.*

8:50 1-01 (Plenary)

CMOS Device Scaling by Nanosheet Channel Architectures and New Channel Materials

*Naoto Horiguchi, *imec (Belgium)*

9:20 1-02 (Plenary)

ALD Nanometer-Thin In₂O₃ for BEOL Logic, Memory and RF Applications

*Peide Ye, *Purdue Univ. (USA)*

Session 2: Machine Learning

Session Chair: Woo Young Choi, *Seoul National University*

9:50 2-01

Data Matching Engine for Efficient Big Data Searching Systems Using a RRAM Based Novel Computing Paradigm

*Shiyue Song^{1,2}, Yizhou Zhang^{1,2}, Jin Kang³, Kai Zheng, Weihai Bu³, Lifeng Liu^{1,2}, Xiaoyan Liu^{1,2}, Jinfeng Kang^{1,2}, Peng Huang^{1,2}, ¹*Peking Univ. (China)*, ²*Beijing Advanced Innovation Center for Integrated Circuits (China)*, ³*Semiconductor Technology Innovation Center (Beijing) Corp. (China)*

10:10 2-02

A Novel Ferroelectric Tunnel FET-based Time-Domain Content Addressable Memory with High Distance-Metric Linearity and Energy Efficiency for Edge Machine Learning

*Weikai Xu¹, Jin Luo¹, Qianqian Huang¹, Ru Huang¹, ¹*Peking University (China)*

10:30 2-03

Machine Learning-based Accurate Single Wafer Wet Etching Amount Prediction

*Shinsei Yoshikiyo¹, Hiroshi Horiguchi², Chihiro Matsui¹, Ken Takeuchi¹, ¹*Univ. of Tokyo (Japan)*, ²*SCREEN Semiconductor Solutions (Japan)*

Break (10 min)

Session 3: Neuromorphic Application I

Session Chair: Steve Chung, *National Yang Ming Chiao Tung Univ.*

11:00 3-01 (Invited talk)

Bayesian Nanoelectronics

*Damien Querlioz, *Université Paris-Saclay (France)*

11:30 3-02

Suppressed Relaxation Effect in TPT-RAM and Dual-mode Neural Network Application

*Xing Mou¹, Xiangpeng Liang¹, Yingjie Lyu², Jianshi Tang¹, Bin Gao¹, Pu Yu², He Qian¹, Huaqiang Wu¹,

¹*School of Integrated Circuits, Tsinghua University (China)*, ²*State Key Laboratory of Low Dimensional Quantum Physics and Department of Physics, Tsinghua University (China)*

11:50 3-03

Synapse Array with Buried Bottom Gate Structure for Neuromorphic Systems

*Bosung Jeon¹, Taejin Jang¹, Seongjae Cho², Hyungcheol Shin¹, Woo Young Choi¹, ¹*Seoul National Univ. (Korea)*, ²*Ewha Womans Univ. (Korea)*

Lunch break (12:10-13:10)

Session 4: Neuromorphic Application II

Session Chair: Kasidit Toprasertpong, *the Univ. of Tokyo*

13:10 4-01 (Invited talk)

In-Materio Reservoir Devices Made of Random Network of Nanomaterials for Application to Smart Sensors and Autonomous Robotics

*Hirofumi Tanaka, *Kyusyu Institute of Tech. (Japan)*

13:40 4-02

FDSOI-based 1T Pixel with Long-term Data Retention for *in-situ* Convolution

*Haozhang Yang¹, Zheng Zhou¹, Guihai Yu¹, Ruiqi Chen¹, Lixia Han¹, Peng Huang¹, Xiaoyan Liu¹, Jinfeng Kang¹, ¹*Peking Univ. (China)*

14:00 4-03

Artificial Nociceptor Based on Short-Term Memory TFT with Controllable Sensitization Level

*Ruiqi Chen^{1,2}, Ruiyi Li^{1,2}, Haozhang Yang^{1,2}, Guihai Yu^{1,2}, Yizhou Zhang^{1,2}, Yiyang Chen^{1,2}, Lianliang Wu^{1,2}, Junchen Dong³, Dedong Han^{1,2}, Zheng Zhou^{1,2}, Peng Huang^{1,2}, Xiaoyan Liu^{1,2}, Jinfeng Kang^{1,2},

¹*School of Integrated Circuits, Peking University (China)*, ²*Beijing Advanced Innovation Center for Integrated Circuits (China)*, ³*Beijing Information Science & Technology University (China)*

Break (10 min)

Session 5: Advanced CMOS Technology

Session Chairs: Masaharu Kobayashi, *Univ. of Tokyo*, Peide Ye, *Purdue Univ.*

14:30 5-01

High Performance Ge FinFET CMOS Inverter with $I_{ON}=2.0$ mA/ μ m at $V_{OV}=1$ V, S.S.=64 mV/dec,

$I_{ON}/I_{OFF}=2.5 \times 10^6$, and Voltage Gain=90 V/V by Using High Pressure Supercritical Fluid Hydroxide Oxidation

*Cheng-Yu Wu¹, Dun-Bao Ruan², Kuei-Shu Chang-Liao¹, Yao-Jen Lee³, Yu-Chuan Chiu⁴, Chih-Wei Liu¹, Guan-Ting Liu¹, Bo-Lien Kuo¹, Kai-Chun Yang¹, Cheng-Han Li¹, Po-Tsun Liu⁴, ¹*National Tsing Hua University (Taiwan)*, ²*Fuzhou University (China)*, ³*Taiwan Semiconductor Research Institute (Taiwan)*, ⁴*National Yang Ming Chiao Tung University (Taiwan)*

14:50 5-02

Enhanced Performance for SiGe/Si Gate-All-Around Field-Effect-Transistor with Ge Condensation Using Supercritical Fluid Treatment

*Wei-Ren Chen¹, Dun-Bao Ruan², Kuei-Shu Chang-Liao¹, Hao-Yan Wang¹, Guang-Li Luo³, Yu-Chuan Chiu⁴, Ting-Kai Kuan¹, Po-Tsun Liu⁴, ¹*National Tsing Hua University (Taiwan)*, ²*Fuzhou University (China)*, ³*Taiwan Semiconductor Research Institute (Taiwan)*, ⁴*National Yang Ming Chiao Tung University (Taiwan)*

15:10 5-03

Thermal consideration in nanoscale gate-all-around vertical transistors

*Guilhem Larrieu¹, Housseem Rezgoui², Abhishek Kumar¹, Jonas Müller¹, Sylvain Pelloquin¹, Yifan Wang², Marina Deng², Aurélie Lecestre¹, Cristell Maneux², Chhandak Mukherjee², ¹*LAAS-CNRS (France)*, ²*IMS laboratory (France)*

15:30 5-04

Thermal and Performance Analysis of Back-side Power Delivery Network beyond 3nm Technology Node

*Haoyu Zhang¹, Linlin Cai¹, Yutao Chen¹, Jianwen Lin¹, Wangyong Chen¹, ¹*Sun Yat-Sen Univ. (China)*

15:50 5-05

Green Laser Crystallized Poly-Si Thin-film Transistor and CMOS Inverter using HfO₂-ZrO₂ Superlattice Gate Insulator and Microwave Annealing for BEOL Applications

*Chih-Hsiang Chang¹, Siao-Cheng Yan¹, Chong-Jhe Sun¹, Ming-Yueh Huang¹, Bo-An Chen¹, Xin-Chan Zhong¹, Yi-Wen Lin¹, Yung-Chun Wu¹, ¹*National Tsing Hua Univ. (Taiwan)*

16:10 5-06

Study of Ferroelectric HfO₂-ZrO₂ Superlattice Poly-Si Junctionless Nanosheet Gate-all-around Field-effect-transistor and CMOS Inverter

*Xin-Chan Zhong¹, Siao-Cheng Yan¹, Ming-Yueh Huang¹, Chih-Siang Chang¹, Chong-Jhe Sun¹, Bo-An Chen¹, Yi-Wen Lin¹, Yung-Chun Wu¹, ¹*National Tsing Hua University (Taiwan)*

Session 6: Poster presentation (poster short presentation 16:40~17:00)

Session Chair: Kuniyuki Kakushima, *Tokyo Tech.*

17:00-18:30 at Syunjyu II

Monday, June 12th, 2023

Session 7: Si Nanoelectronics & Device Physics

Session Chair: Takahide Oya, *Yokohama National Univ.*

8:50 7-01 (invited talk)

Silicon Electron Nano-Aspirator - Current enhancement based on electron-electron scattering –

*Yukinori Ono, *Shizuoka Univ. (Japan)*

9:20 7-02

Effects of Quantum Confinement on Charge-Based Threshold Voltage Definition

*Kiyoshi Takeuchi¹, Masaharu Kobayashi¹, Toshiro Hiramoto¹, ¹*Univ. of Tokyo (Japan)*

9:40 7-03

An Enhanced AC Conductance Method with Source/Drain Resistance Correction for Self-Heating Effects of Novel Nano-Scaled Devices

*Jyun-Yan Kuo¹, Wei Lee¹, Ke-Wei Su¹, Chung-Kai Lin¹, ¹*Taiwan Semiconductor Manufacturing Company (Taiwan)*

10:00 7-04

Drag of Electron-Hole Bilayer in Silicon-on-Insulator at Low Temperature

*Ahmed Nabil¹, Manjakavahoaka Razanoelina¹, Masahiro Hori¹, Akira Fujiwara², Yukinori Ono¹, ¹*Shizuoka Univ. (Japan)*, ²*NTT Basic Research Laboratory (Japan)*

10:20 7-05

Modification and Ablation of Thin Silicon-on-Insulator Films by fs-Laser

*Daniel Moraru^{1,2}, Tsutomu Kaneko¹, Daniel Smith², Tomas Katkus², Soon Hock Ng², Saulius Juodkazis², ¹*Shizuoka Univ. (Japan)*, ²*Swinburne Univ. of Tech. (Australia)*

Break (10 min)

Session 8: Quantum dots

Session Chair: Pei-Wen Li, *National Yang Ming Chiao Tung Univ.*

10:50 8-01 Integrable Germanium Few-Hole Double Quantum-Dots and Single-Hole Transistors using CMOS Fabrication Approaches

*Chi-Cheng Lai¹, I-Hsiang Wang¹, Ting Tsai¹, Horng-Chih Lin¹, Pei-Wen Li¹, ¹*National Yang Ming Chiao Tung University (Taiwan)*

11:10 8-02 Single-Electron Charge Sensor Self-Aligned to a Quantum Dot Array by Double-Gate Patterning Process for a Large-Scale Silicon Quantum Computer

*Takuma Kuno¹, Takeru Utsugi¹, Ryuta Tsuchiya¹, Noriyuki Lee¹, Gou Shinkai¹, Toshiyuki Mine¹, Itaru Yanagi¹, Raisei Mizokuchi², Jun Yoneda², Tetsuo Kodera², Shinichi Saito¹, Digh Hisamoto¹, Hiroyuki Mizuno¹, ¹*Hitachi, Ltd. (Japan)*, ²*Tokyo Institute of Technology (Japan)*

11:30 8-03 Individual Control of Characteristics of Vertically Stacked Silicon Quantum Dots

*Junoh Kim¹, Tomoko Mizutani¹, Takuya Saraya¹, Hiroshi Oka², Takahiro Mori², Masaharu Kobayashi^{1,3}, Toshiro Hiramoto¹, ¹*IIS, Univ. of Tokyo (Japan)*, ²*AIST (Japan)*, ³*d.lab, Univ. of Tokyo (Japan)*

11:50 8-04 Structural and Electrostatic Confinement of a Single Electron in a Scalable 2D Array

of Quantum Dots

*Amina Sadik¹, Etienne Nowak¹, Louis Hutin¹, Pierre-André Mortemousque¹, Benoit Bertrand¹, ¹*CEA-Leti, Univ. of Grenoble Alpes (France)*

Lunch break (12:10-13:10)

Session 9: Application of 2D material

Session Chair: Daniel Moraru, *Shizuoka, Univ.*

13:10 9-01 (invited talk)

Graphene Based NEMS and Electric Field Sensor: From Research to Real-World Applications

*Afsal Kareekunnnan¹, Manoharan Muruganathan¹, Ngoc Huynh Van¹, Marek E Schmidt¹, Takeshi Kudo², Takeshi Maruyama², Hiroshi Mizuta^{1,3}, ¹*JAIST (Japan)*, ²*Otowa Elec. (Japan)*, ³*Univ. Southampton (UK)*

13:40 9-02

Novel MoS₂ Dual-Gate FET with a Highly Scaled EOT of ~2.4 nm High-k Gate Dielectric Layer for Reconfigurable Logic Gate and High-Precision Analog Synapse

*Lingqi Li¹, Haofei Zheng¹, Heng Xiang¹, Yu-Chieh Chien¹, Kah-Wee Ang^{1,2}, ¹*Department of Electrical and Computer Eng., National Univ. of Singapore (Singapore)*, ²*Inst. of Materials Res. and Eng., A*STAR (Singapore)*

14:00 9-03

Forming-Free Resistive Switching by Lateral Ag Ion Migration on MoS₂

*Sofia Cruces¹, Lukas Voelkel¹, Jimin Lee¹, Dennis Braun¹, Ardeshir Esteki¹, Annika Grundmann², Holger Kalisch², Michael Heuken^{2,3}, Andrei Vescan², Alwin Daus¹, Max Christian Lemme^{1,4}, ¹*Chair of Electronic Devices, RWTH Aachen Univ. (Germany)*, ²*Compound Semiconductor Tech., RWTH Aachen Univ. (Germany)*, ³*AIXTRON SE (Germany)*, ⁴*AMO GmbH (Germany)*

14:20 9-04

Scalability of h-BN Based Memristors: Yield and Variability Considerations

Abdelrahman S. Abdelrahman¹, Hesham ElSawy², Mario Lanza³, Deji Akinwande⁴, *Feras Al-Dirini^{1,5}, ¹*Electrical Engineering Department, King Fahd University of Petroleum & Minerals (Saudi Arabia)*, ²*School of Computing, Queen's University (Canada)*, ³*Physical Science and Engineering Division, King Abdullah University of Science and Technology (Saudi Arabia)*, ⁴*Microelectronics Research Center, The University of Texas at Austin (United States of America)*, ⁵*Center for Advanced Materials, King Fahd University of Petroleum & Minerals (Saudi Arabia)*

Break (10 min)

Session 10: Memory Technology

Session Chairs: Minoru Oda, *KIOXIA Cooperation*

14:50 10-01

A 40-nm Loadless 4T-SRAM TRNG MACRO with Read-just-after-write (RAW) Scheme Featuring 5.3Gb/s and 3.64TOP/W

Y. S. Wu¹, K. H. Chang¹, P. S. Huang¹, M. L. Miu¹, S. Y. Huang¹, S. M. Lu¹, H. S. Su¹, *E Ray Hsieh¹, ¹*National Central University (Taiwan)*

15:10 10-02

Record-High Memory Window and Robust Retention Anti-Fuse OTP Memory: Electrical and Reliability Characteristics

Dong Ru Hsieh¹, *Jia Chian Ni¹, Wei Ju Yeh¹, Tzu Chieh Hong¹, Zi Yang Hong¹, Yan Kui Liang¹, Huai En Luo¹, Michael Hsu¹, Ta Chun Cho², Tien Sheng Chao¹, ¹*National Yang Ming Chiao Tung Univ. (Taiwan)*, ²*Taiwan Semiconductor Res. Inst. (Taiwan)*

15:30 10-03

Physical Understanding on the Anti-fuse Instability to Construct a Selector-Type One-Time-Programming Memory in the High-k Metal-Gate CMOS Generation

C. C. Chuang¹, C. W. Chang¹, H. W. Chen¹, *T. C. Kao¹, Y. J. Li¹, J. C. Guo¹, Steve S Chung¹, ¹*National Yang Ming Chiao Tung Univ. (Taiwan)*

15:50 10-04

Physical mechanisms and Enhancement of Endurance Degradation of SiO_x: Ag-based Volatile Memristors

*Ruiyi Li^{1,2}, Haozhang Yang^{1,2}, Yizhou Zhang^{1,2}, Xujin Song^{1,2}, Nan Tang^{1,2}, Ruiqi Chen^{1,2}, Zheng Zhou^{1,2}, Weihai Bu³, Kai Zheng³, Jin Kang³, Lifeng Liu^{1,2}, Jinfeng Kang^{1,2}, Peng Huang^{1,2}, ¹*Peking University (China)*, ²*Beijing Advanced Innovation Center for Integrated Circuits (China)*, ³*Semiconductor Technology Innovation Center (Beijing) Corporation (China)*

16:10 10-05

Stand-alone STT-MRAM development on VCT transistor in 0.0045 μm² unit cell

Jaewoo Kim¹, *Qiong Tuo¹, Handong Xu¹, Yali Tan¹, Tingting Gu¹, Haiyang Dong¹, Xingkun Xue¹, Zelun Li¹, Kuoming Huang¹, Zhonghan Cao¹, Bowen Dong², Kaifeng Dong³, Huihui Li², Chao Zhao², Abraham Yoo¹, ¹*ChangXin Memory Tech., Inc. (China)*, ²*Superstring Academy of Memory Tech. (China)*, ³*China Univ. of Geosciences (China)*

Break (10 min)

Session 11: Ferroelectric devices

Session Chairs: Katsuhiko Nishiguchi, *NTT Basic Research laboratories*

16:40 11-01 (invited talk)

Stacked Gate-All-Around Nanosheet Channel Ferroelectric Hf_xZr_{1-x}O₂ FETs With NH₃ Plasma Treatment Featuring High Footprint Current

Dong-Ru Hsieh, Chia-Chin Lee, *Tien-Sheng Chao, *National Yang Ming Chiao Tung University (Taiwan)*

17:10 11-02

New Insights into the Memory Window Estimation in FeFET from a Dynamic Perspective

*Puyang Cai¹, Hao Li¹, Chang Su¹, Tianxiang Zhu¹, Lining Zhang¹, Runsheng Wang¹, Ru Huang¹, ¹*Peking University (China)*

17:30 11-03

Investigation of HfO₂/ZrO₂ Superlattice Dielectric and High-k AlON Interfacial Layer on Ferroelectric FinFET

*Ming-Yueh Huang¹, Siao-Cheng Yan¹, Xin-Chan Zhong¹, Chih-Siang Chang¹, Chong-Jhe Sun¹, Bo-An Chen¹, Yi-Wen Lin¹, Yung-Chun Wu¹, ¹*National Tsing Hua Univ. (Taiwan)*

17:50 11-04

Vertically Stacked Ge Diamond-shape Nanowires GAAFET with Ferroelectric HZO

*Bo-An Chen¹, Yi-Wen Lin¹, Hao-Hsiang Chang¹, Chih-Hsiang Chang¹, Ming-Yueh Huang¹, Xin-Chan Zhong¹, Siao-Cheng Yan¹, Chong-Jhe Sun¹, Fu-Ju Hou², Yung-Chun Wu¹, ¹*National Tsing Hua Univ. (Taiwan)*, ²*Taiwan Semiconductor Research Inst. (Taiwan)*

18:10 Closing remarks

Kuniyuki Kakushima, *Tokyo Tech.*

Poster Presentation (June 11th, 17:00-18:30, with poster short presentation 16:40~17:00)

P01

Performance Improvement of Single-Electron Reservoir Computing Circuit with Multiple-Tunnel-Junction Single Electron Oscillator

*Shunya Watanabe¹, Takahide Oya¹, ¹*Yokohama National Univ. (Japan)*

P02

Single-Electron Information-Processing Circuit Inspired by Principles of Molecular Computing

*Kairi Yokoyama¹, Takahide Oya¹, ¹*Yokohama National Univ. (Japan)*

P03

Logically Synthesized Invertible Logic Based on Many-body Effects with Probabilistic-bit Implementation

*Yihan He¹, Chao Fang¹, Sheng Luo¹, Gengchiao Liang¹, ¹*National Univ. of Singapore (Singapore)*

P04

Influence of Weight Transfer Error on Vector-Matrix Multiplication Using AND Array Architectures

*Junsu Yu¹, Donghyun Ryu¹, Taejin Jang¹, Woo Young Choi¹, ¹*Seoul National Univ. (Korea)*

P05

Experimental Demonstration of Memristor Delay-Based Logic In-Memory Ternary Neural Network

Adrien Renaudineau¹, Kamel-Eddine Harabi¹, Clément Turck¹, Axel Laborieux¹, Elisa Vianello², Marc Boquet³, Jean-Michel Portal³, *Damien Querlioz¹, ¹*Univ. Paris-Saclay, CNRS, C2N (France)*, ²*CEA-LETI, Univ. Grenoble-Alpes (France)*, ³*Aix-Marseille Univ., CNRS, IM2NP (France)*

P06

A Crossbar-wise IR-drop Compensation Schemes for 5G/6G Hybrid Precoding with Highly-parallel Analog RRAM Array

*Qi Qin¹, Qingtian Zhang¹, Bin Gao¹, Jianshi Tang¹, He Qian¹, Huaqiang Wu¹, ¹*Tsinghua Univ. (China)*

P07

Ultra-Large Memory Window of 3.8V and 75% Read/Write Speed Improvement through Stressed Alumina and Angstrom-Laminated HfZrO₂

*Zi-Rong Huang¹, Sheng Min Wang¹, Cheng Rui Liu¹, Yu Ting Chen¹, Yu Tzu Cai¹, Zheng Kai Chen¹, Chia Shou Pai¹, Ying Tsan Tang¹, ¹*National Central Univ. (Taiwan)*

P08

Optimization of Ferroelectricity in Al-Doped HfO₂ Capacitors: Electrical and Endurance Characteristics

*Dong Ru Hsieh¹, Huai En Luo¹, Jia Chian Ni¹, Zi Yang Hong¹, Yi Hsiu Chen¹, Wei Ju Yeh¹, Tien Sheng Chao¹, ¹*National Yang Ming Chiao Tung Univ. (Taiwan)*

P09

Improved Switching behaviors of MFM Capacitor with Reduced E_c and Enhanced P_r-V Linearity by Using La-Al co-doped HfO₂ Ferroelectric layer

*Xujin Song¹, Haolin Li¹, Zhuohua Tang¹, Peng Huang¹, Xiaoyan Liu¹, Jinfeng Kang¹, ¹*Peking Univ. (China)*

P10

Variability Analysis of Stacked-Nanosheet FeFET for MLC Memory and Synapse Applications

*Heng Li Lin¹, Pin Su¹, ¹*Univ. of National Yang Ming Chiao Tung (Taiwan)*

P11

New Understanding of Memory Window Reduction Induced by Ferroelectric Dynamics for HfO₂-based 1T1C FeRAM

*Zhiyuan Fu¹, Mengxuan Yang¹, Kaifeng Wang¹, Qianqian Huang^{1,2,3}, Ru Huang^{1,2}, ¹*Peking Univ. (China)*, ²*Beijing Advanced Innovation Center for Integrated Circuits (China)*, ³*Beijing Superstring Academy of Memory Tech. (China)*

P12

~~(Withdrawn) Impact of Fringing Field on the Memory Window of FeFET~~

~~*Athira Sunil⁺, Maximilian Lederer⁺, Yannick Raffel⁺, Franz Müller⁺, Konrad Seidel⁺, Thomas Kämpfe⁺, Sourav De⁺, ⁺*Fraunhofer Institute for Photonic Microsystems (Germany)*~~

P13

Impact of Si-Based Interfacial Layer for Ferroelectric Memory

*Siddheswar Maikap^{1,2}, Asim Senapati¹, Zhao-Feng Lou³, Min-Hung Lee³, ¹*Chang Gung Univ. (Taiwan)*, ²*Keelung Chang Gung Memorial Hospital (Taiwan)*, ³*National Taiwan Normal Univ. (Taiwan)*

P14

~~(Withdrawn) A Comprehensive Understanding for AFeFET with Double Hysteresis Loop Model: Guidelines for Performance and Reliability~~

~~*Min Liao⁺, Junshuai Chai⁺, Jinjuan Xiang², Kai Han³, Yanrong Wang⁴, Hao Xu⁺, Xiaolei Wang⁺, Jing Zhang⁴, Wenwu Wang⁺, ⁺*Inst. of Microelectronics Chinese Academy of Sciences (China)*, ²*Beijing Superstring Academy of Memory Tech. (China)*, ³*Weifang Univ. (China)*, ⁴*North China Univ. of Tech. (China)*~~

P15

In-Solution Germanium Selenide Nanosheets as Charge Trapping Layer in Flash Memories

Nazek El-Atab¹, *Bashayr Ali Alqahtani¹, ¹*Program of Electrical and Computer Engineering, King Abdullah Univ. of Sci. and Tech. (Saudi Arabia)*

P16

Spherical Shallow Trench Isolation with silicon nitride layer in Buried Gate DRAM for reducing pass gate disturbance

*Yeon-Seok Kim^{1,2}, Chang-Young Lim^{1,2}, Min-Woo Kwon^{1,2}, ¹*National Univ. of Gangneung-Wonju (Korea)*, ²*Lab. of ISDL (Korea)*

P17

A Physics-based Numerical Model of Resistive Switching Behavior in Electrochemical Metallization Memristor

*Yeongkwon Kim¹, Byung Chul Jang¹, ¹*Kyungpook Nat'l Univ. (Korea)*

P18

A High-Speed and Self-calibratable True Random Number Generator (TRNG) based on Unified Selector-RRAM

*Yabo Qin¹, Zongwei Wang^{1,2}, Jiajun Gao¹, Linbo Shan¹, Qishen Wang¹, Yimao Cai^{1,2}, Ru Huang^{1,2}, ¹*Peking*

Univ. (China), ²Beijing Adv. Innovation Center for IC (China)

P19

Generative Network Utilizing Random Number Based on Memristor Array for Medical Image Synthesis

*Namju Kim¹, Byung Chul Jang¹, ¹*Kyungpook Nat. Univ. (Korea)*

P20

Design of New Single-Electron Reaction-Diffusion Circuit with Ability to Generate and Control Plane Waves

*Keiichiro Tamura¹, Yuito Nakamori¹, Takahide Oya¹, ¹*Yokohama National Univ. (Japan)*

P21

Theoretical Study of High Performance Germanium Nanowire Quantum Dot

*Han-Wei Yang¹, Yung-Feng Wu¹, Ming-Jung Hsu¹, Shao-Chen Lee¹, Ying-Tsan Tang¹, ¹*National Central University (Taiwan)*

P22

Enhanced Electrical Performance of Ge nMOSFET with Rapid Remote Plasma Oxidation Treatment

*Jia-Cheng Liu¹, Dun-Bao Ruan², Kuei-Shu Chang-Liao¹, Guan-Ting Liu¹, ¹*National Tsing Hua University (Taiwan)*, ²*Fuzhou University (China)*

P23

Improved Radiation Hardness for Nanosheet FETs with Partial Bottom Dielectric Isolation

*Xun-Ting Zheng¹, Vita Pi-Ho Hu¹, ¹*National Taiwan University (Taiwan)*

P24

Phosphorus Deactivation and Electron Mobility Enhancement in Ultrathin Silicon Nanosheets

*Michele Perego¹, Andrea Pulici^{1,2}, Stefano Kuschnan^{1,3}, Gabriele Seguin¹, Fabiana Taglietti², Marco Fanciulli^{1,2}, Riccardo Chiarcos³, Michele Laus³, ¹*CNR-IMM Unit of Agrate (Italy)*, ²*Università degli Studi di Milano-Bicocca (Italy)*, ³*Università del Piemonte Orientale "A. Avogadro" (Italy)*

P25

Performance Investigation of Source/Drain Extension Region on Nanosheet FET: A Digital Design Perspective

*Shobhit Srivastava¹, Sourabh Panwar¹, Shashidhara M.¹, Navjeet Bagga², Deepak Joshi¹, Abhishek Acharya¹, ¹*Sardar Vallabhbhai National Institute of Technology, Surat, Gujarat (India)*, ²*IIT Bhubaneswar, Odisha (India)*

P26

Comprehensive Investigation of Back Gate Biasing on Performance of Line TFETs

*Sourabh Panwar¹, Shobhit Srivastava¹, Shashidhara M¹, Prabhat Dubey², Deepak Joshi¹, Abhishek Acharya¹, ¹*Sardar Vallabhbhai National Institute of Technology, SVNIT (India)*, ²*Univ. of Pisa (Italy)*

P27

Atomically Thin 0.65nm and 6nm Vertical Side-Wall MoS₂ Channel Transistors

*Kihan Kim¹, Byung Chul Jang¹, ¹*Kyungpook National Univ. (Korea)*